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| Notice of References Cited | Application/Control No. 10/509,308 | Applicant(s)/Patent Under Reexamination ABIKO ET AL. | |
| | Examiner HENOK G. HEYI | Art Unit 2627 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--|-----------------|-----------------|----------------|
| * | A US-6,218,292 B1 | 04-2001 | Foote, David K. | 438/636 |
| * | B US-2001/0005350 A1 | 06-2001 | Kitaura et al. | 369/94 |
| * | C US-2001/0012257 A1 | 08-2001 | Suzuki et al. | 369/94 |
| * | D US-2002/0024913 A1 | 02-2002 | Kojima et al. | 369/94 |
| * | E US-2003/0044719 A1 | 03-2003 | Katoh et al. | 430/270.13 |
| * | F US-2003/0138669 A1 | 07-2003 | Kojima et al. | 428/694.0ST |
| * | G US-2003/0161988 A1 | 08-2003 | Hwang et al. | 428/64.4 |
| * | H US-6,606,293 B1 | 08-2003 | Okada et al. | 369/94 |
| | I US- | | | |
| | J US- | | | |
| | K US- | | | |
| | L US- | | | |
| | M US- | | | |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|-----------------|---------|------|----------------|
| | N | | | | |
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| | P | | | | |
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NON-PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|-----------------|---------|------|----------------|
| | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | | |
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

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